

Program

22 May 2011
15:00 – 18:00

LAYTEC 14th IN-SITU SEMINAR

Berlin, Maritim proArte Hotel
Salon 2 (upstairs)

Time	Speaker	Topic
14:00 – 15:00		Lunch (Restaurant Galerie)
15:00 – 15:10	Dr. Thomas Zettler LayTec	Welcoming words
15:10 – 15:30	Henning Döscher Helmholtz-Zentrum Berlin	In-situ characterization of surface properties in MOVPE ambient
15:30 – 16:00	Prof. Masakazu Sugiyama University of Tokyo	Simultaneous use of in-situ curvature measurement and XRD diffraction for structural optimization of InGaAs/GaAsP quantum-well solar-cells
16:00 – 16:15	Dr. Oliver Schulz LayTec	Current products for in-situ control of semiconductor epitaxy
16:15 – 16:35		Coffee break
16:35 – 16:50	Dr. Konstantin Pötschke Heinrich-Hertz-Institut Berlin	EpiRAS for thickness control of InP-based optoelectronic devices
16:50 – 17:10	Dr. André Maaßdorf Ferdinand-Braun-Institut	In-situ curvature measurements of MOVPE-grown GaAs/AlGaAs structures
17:10 – 17:30	Dr. Martin Zorn JENOPTIK	EpiTT applied to MOVPE growth of AlGaAs-based laser structures
17:30 – 17:45	Dr. Kolja Haberland LayTec	New products and developments
17:45 – 18:00	Discussion	